

Search Notes



Application/Control No.

09/925,259

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

ADAMS ET AL.

Art Unit

3629

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| 705 | 1 | 9/05 | DN |
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| | 8 | | |
| | 26 | | |
| 703 | 1 | | |
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| 706 | 46 | | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|-------------|------|------|
| I US Patent | 9/05 | DN |
| US PG Pub | | |
| II FOREIGN | | |
| 1. EPO | | |
| 2. JPO | | |
| 3. Derwent | | |
| 4. IBM-TDB | | |
| 5. Derwent | | |
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